



AI Test

Guest Editors:

Prof. Dr. Hong Zhu

School of Engineering,
Computing and Mathematics,
Oxford Brookes University,
Oxford OX33 1HX, UK

Prof. Dr. Junhua Ding

Department of Information
Science, University of North
Texas, Denton, TX 76203, USA

Prof. Dr. Aktouf Oum-El-Kheir

Grenoble INP*, University
Grenoble Alpes, LCIS, 26000
Valence, France

Deadline for manuscript
submissions:

closed (31 January 2024)

Message from the Guest Editors

Dear Colleagues,

Topics of interest include, but are not limited to:

- Quality models, quality attributes and metrics for AI applications, such as robustness, fairness, reliability and performance.
- Testing methods, techniques and tools for various aspects and activities of testing and quality assurance, especially for test case generation, test oracle, and test adequacy measurements.
- Test automation environment and platforms for AI applications and by employing AI techniques.
- Domain specific testing techniques and methods for various special domains of AI applications, such as AI applications in natural language processing such as ChatGPT, image recognitions, time series and Internet of Things data analysis, medical and healthcare, robotics, software code generation/debugging/design, etc.
- Testing and quality assurance for various specific AI techniques, such as clusters and classifiers, regression machine learning models, deep neural networks, big models, recurrent neural networks, etc.





an Open Access Journal by MDPI

Editor-in-Chief

Prof. Dr. Flavio Canavero

Department of Electronics and
Telecommunications,
Politecnico di Torino, 10129
Torino, Italy

Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

Author Benefits

Open Access: free for readers, with article processing charges (APC) paid by authors or their institutions.

High Visibility: indexed within Scopus, SCIE (Web of Science), CAPlus / SciFinder, Inspec, Ei Compendex and other databases.

Journal Rank: JCR - Q2 (*Physics, Applied*) / CiteScore - Q2 (*Control and Systems Engineering*)

Contact Us

Electronics Editorial Office
MDPI, Grosspeteranlage 5
4052 Basel, Switzerland

Tel: +41 61 683 77 34
www.mdpi.com

mdpi.com/journal/electronics
electronics@mdpi.com
[X@electronicsMDPI](https://x.com/electronicsMDPI)